

2 048-BIT CCD LINEAR IMAGE SENSOR WITH PERIPHERAL CIRCUITS

The μPD3593 is a 2048-bit high sensitivity CCD (Charge Coupled Device) linear image sensor which changes optical images to electrical signal.

The μPD3593 has an output amplifier which has wide output range, and which can switch gain. Therefore easy to get signal level which is easy to process from low illumination to high illumination, and it is easy to apply to many purposes.

With internal generation circuit of driving signal and internal driver, the μPD3593 performs only with two basic clock inputs. No special driving circuit is required. In addition, analog signal processor convert and output independent CCD register in every bit to continuous video signal. So it is easy to interface to A/D converter or Bi-level converter.

FEATURES

- Valid photocell 2 048-bit
- Photocell's pitch 14 μm
- CCD output 4 steps selectable gain (2, 4, 8, 16 times)
- Peak response wavelength 550 nm (green)
- Resolution 8 dot/mm across the shorter side of a B4-size (257 x 364 mm) sheet
- Power supply +12 V, +5 V
- Drive clock level CMOS 5 V clock input x 2
- High speed scan 1 ms/line
- Built-in circuit Timing generator
CCD clock driver
Optical black clamp circuit
Sample and hold circuit
4-step variable gain amplifier

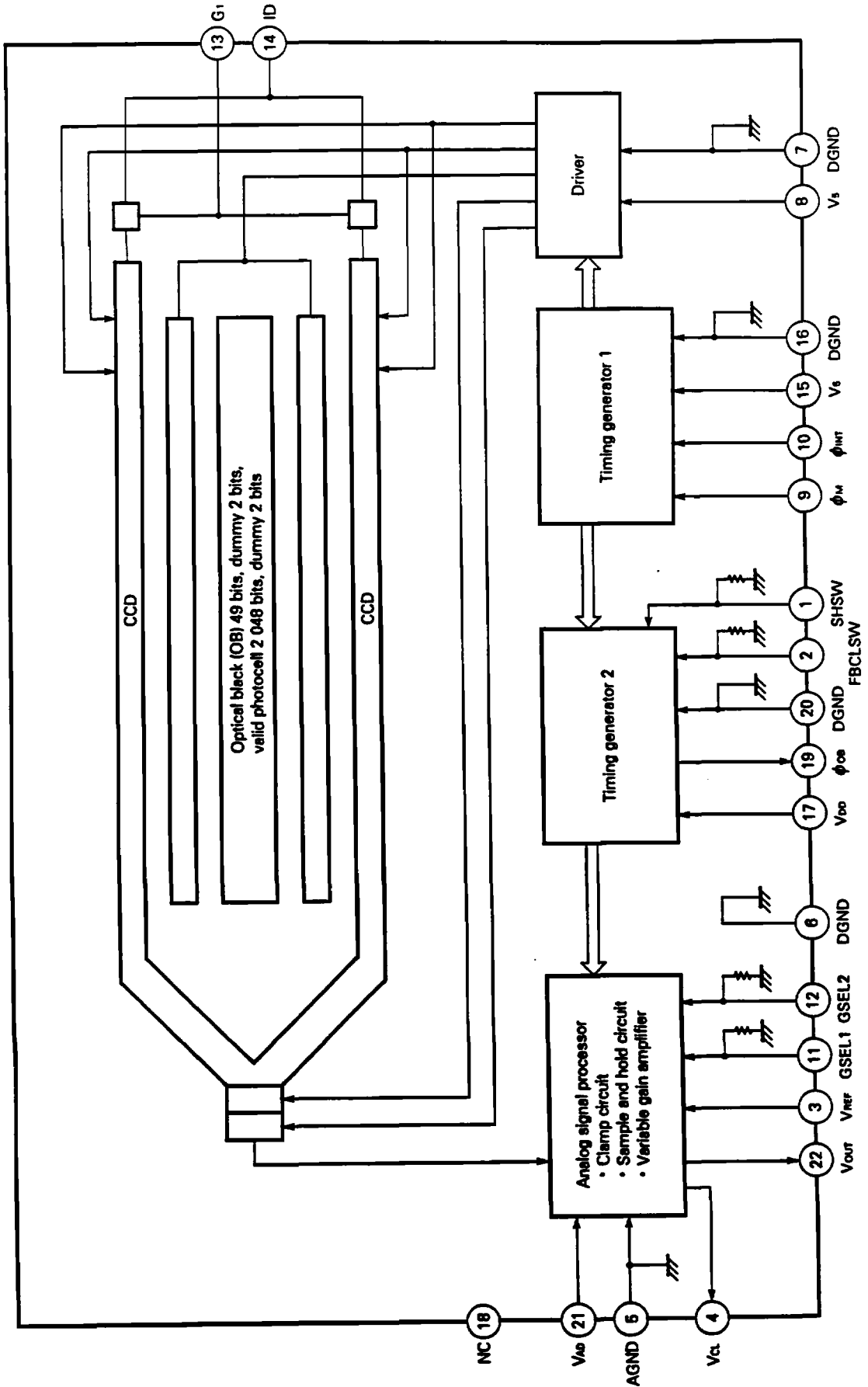
ORDERING INFORMATION

Part Number	Package	Quality Grade
μPD3593D	22-pin ceramic DIP (CERDIP) (400 mil)	Standard

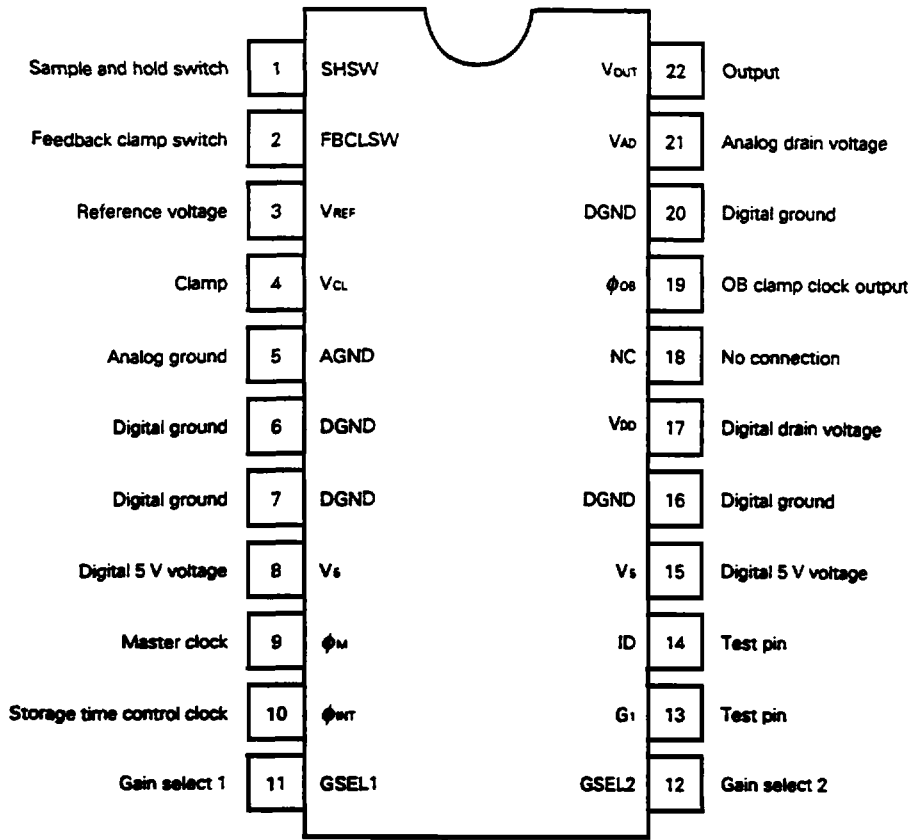
Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

The information contained in this document is being issued in advanced of the production cycle for the device. The parameters for the device may change before final production or NEC Corporation, at its own discretion, may withdraw the device prior to its production.

2 BLOCK DIAGRAM



PIN CONFIGURATION (Top View)



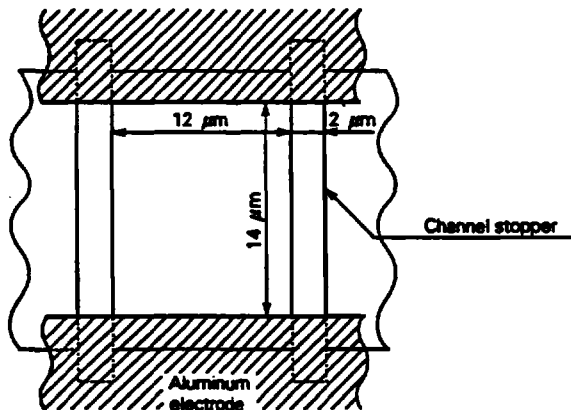
Function of SHSW pin

SHSW	Sample and hold circuit
V _s	Stop
0 V	Operate

Function of FBCLSW pin

FBCLSW	Feedback clamp circuit
V _s	Stop
0 V	Operate

PHOTOELEMENT STRUCTURE DIAGRAM



ABSOLUTE MAXIMUM RATINGS (T_a = 25 ° C)

Parameter	Symbol	Ratings	Unit
Analog drain voltage	V _{AD}	-0.3 ~ +15	V
Digital drain voltage	V _{DD}	-0.3 ~ +15	V
Test pin ID voltage	V _{ID}	-0.3 ~ +15	V
Digital 5 V voltage	V _S	-0.3 ~ +7	V
Reference voltage	V _{REF}	-0.3 ~ +7	V
Clamp pin input voltage	V _{CL}	-0.3 ~ +7	V
Sample and hold switch	V _{SHSW}	V _S	V
Feedback clamp switch	V _{FBCLSW}	V _S	V
Master clock voltage	V _{φM}	V _S	V
Storage time control clock voltage	V _{φST}	V _S	V
Gain select input voltage 1	V _{GSEL1}	V _S	V
Gain select input voltage 2	V _{GSEL2}	V _S	V
Operating ambient temperature	T _{OPT}	-25 ~ +60	° C
Storage temperature	T _{STG}	-40 ~ +100	° C

RECOMMENDED OPERATING CONDITIONS (T_a = -25 to + 60 ° C)

Parameter	Symbol	MIN.	TYP.	MAX.	Unit
Analog drain voltage	V _{AD}	11.4	12.0	12.6	V
Digital drain voltage	V _{DD}	11.4	12.0	12.6	V
Test pin ID voltage	V _{ID}	11.4	12.0	12.6	V
Digital 5 V voltage	V _S	4.5	5.0	5.5	V
Reference voltage	V _{REF}	4.0	4.5	5.0	V
Master clock φ _M signal high level	V _{φMH}	4.5	V _S	V _S	V
Master clock φ _M signal low level	V _{φML}	-0.3	0	0.5	V
Storage time control clock φ _{ST} signal high level	V _{φSTH}	4.5	V _S	V _S	V
Storage time control clock φ _{ST} signal low level	V _{φSTL}	-0.3	0	0.5	V
Gain select input voltage GSEL 1,2 signal high level	V _{φGSELH}	4.5	V _S	V _S	V
Gain select input voltage GSEL 1,2 signal low level (Note 1)	V _{φGSELL}	-0.3	0	0.5	V
Sample and hold switch SHSW signal high level	V _{φSHH}	4.5	V _S	V _S	V
Sample and hold switch SHSW signal low level (Note 1)	V _{φSHL}	-0.3	0	0.5	V
Feedback clamp switch FBCLSW signal high level	V _{φFBCLH}	4.5	V _S	V _S	V
Feedback clamp switch FBCLSW signal low level (Note 1)	V _{φFBCLL}	-0.3	0	0.5	V
Hold capacitor (Note 2)	C _H	—	0.001	0.01	μF
Master clock φ _M frequency	f _{φM}	0.5	2	4	MHz

Note 1. Gain select pin (GSEL 1, 2), sample and hold switch pin (SHSW), feedback clamp switch pin (FBCLSW) are pull down to GND internally with 50 kΩ ~ 200 kΩ resistor.

2. Control voltage hold capacitor depending on storage time (T_{STG}).

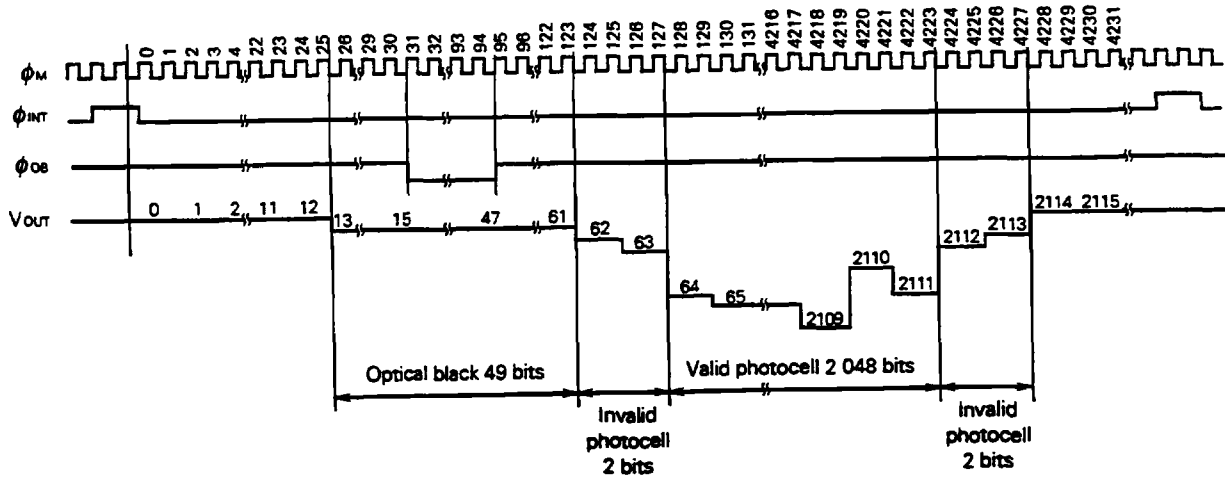
ELECTRICAL CHARACTERISTICS

T_a = 25 ° C, V_{AD} = V_{DD} = 12 V, V_S = 5 V, f_{PM} = 2 MHz, data rate = 1 MHz, storage time = 10ms
 input signal clock = 5 V_{P-P}, V_{REF} = 4.5 V, light source = 3200 K halogen lamp + C500 (infrared cut filter)

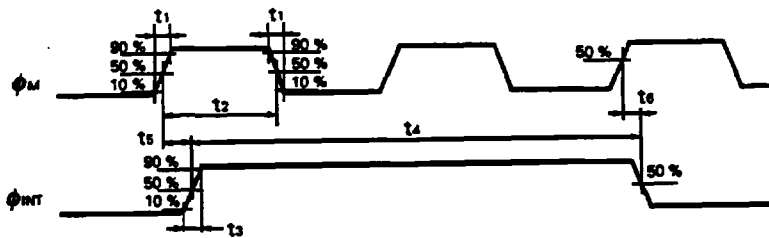
Parameter	Symbol	Test Conditions			MIN.	TYP.	MAX.	Unit	Built-in amplifier gain	
			GSEL1	GSEL2						
Saturation voltage	V _{SAT}	Daylight color fluorescent lamp	—	—	2	3	—	V		
Saturation exposure	SE	Daylight color fluorescent lamp	0	0	—	0.114	—	lx·s		x2
			0	1	—	0.051	—			x4
			1	0	—	0.027	—			x8
			1	1	—	0.012	—			x16
Photo response non-uniformity	PRNU	V _{OUT} = 500 mV	0	0	—	±4	±8	%		
Average dark signal	ADS	T _C = 25 ° C ^{Note} , T _{INT} = 10 ms light shielding	0	0	—	1	5	mV		x2
			0	1	—	2	10			x4
			1	0	—	4	20			x8
			1	1	—	8	40			x16
Dark signal non-uniformity	DSNU	T _C = 25 ° C ^{Note} , T _{INT} = 10 ms light shielding	0	0	-5	±1	+5	mV		x2
			0	1	-10	±2	+10			x4
			1	0	-20	±4	+20			x8
			1	1	-40	±8	+40			x16
Power consumption	P _w	V _{DD} = V _{DD} = 12 V V _S = 5 V, f _{PM} = 2 MHz	0	0	150	230	350	mW		
			1	1	80	120	180			
Output impedance	Z _o		0	0	-	1	2	kΩ		
Response	R _f	Daylight color fluorescent lamp	0	0	18.5	26.4	34.3	V/lx·s		x2
			0	1	—	59.4	—			x4
			1	0	—	110	—			x8
			1	1	—	248	—			x16
Response peak wavelength			—	—	—	550	—	nm		
Image lag	IL	V _{OUT} = 1 V	0	0	—	2	5	%		
Reference voltage input current	I _{REF}		0	0	—	0.001	0.1	mA		
Transfer efficiency	TTE	V _{OUT} = 500 mV	0	0	92	98	—	%		
Sample and hold noise	SHN	light shielding	0	0	—	15	30	mV		
Clamp error	V _{ERR}	light shielding V _{REF} = 4.5 V	0	0	-100	0	+100	mV		
Clock input capacitance Master clock input pin Storage time control clock input pin	C _φ		—	—	—	5	10	pF		
Pull down resistor Gain select input pin Sample and hold switch pin Feedback clamp switch pin	R _{PD}	V _{IN} = 5 V	—	—	50	100	200	kΩ		
Resister imbalance	RI	V _{OUT} = 500 mV	0	0	—	—	3	%		
Dynamic range	DR	V _{SAT} /DSNU	0	0	—	3000	—	times		x2
			0	1	—	1500	—			x4
			1	0	—	750	—			x8
			1	1	—	375	—			x16

Note T_c = Case temperature

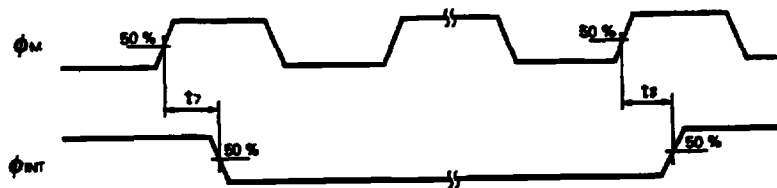
TIMING CHART



Timing Chart for ϕ_M and ϕ_{INT}



ϕ_{OB} Signal Delay from ϕ_M

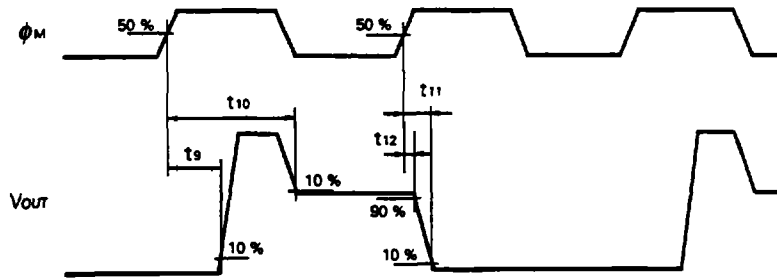


Recommended Timing

(Unit: ns)

Parameter	MIN.	TYP.	MAX.
t_1	0	20	100
t_2	125	250	1000
t_3	0	20	100
t_4	—	$4t_2$	—
t_5	-30	0	t_2
t_6	$-t_2$	0	t_2

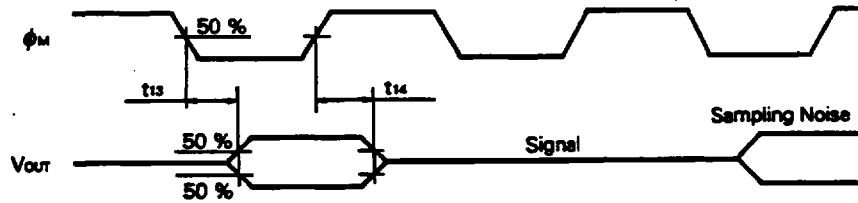
V_{out} Signal Delay from ϕ_M (SHSW pin = V_s)



Signal Delay Time at V_{out} = 500 mV (Unit: ns)

Parameter	MIN.	TYP.	MAX.
t ₇	200	280	370
t ₈	150	220	290
t ₉	40	60	80
t ₁₀	160	230	300
t ₁₁	66	95	125
t ₁₂	40	60	80

V_{out} Signal Delay from ϕ_M (SHSW pin = 0 V)



Signal Delay Time (Unit: ns)

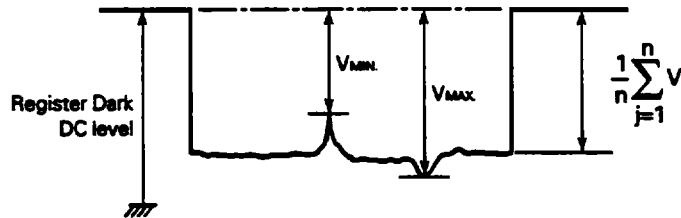
Parameter	MIN.	TYP.	MAX.
t ₁₃		80	120
t ₁₄		50	100

DEFINITIONS OF CHARACTERISTIC ITEMS

1. **Saturation voltage: V_{SAT}**
Output signal voltage at which the response linearity is lost.
2. **Saturation exposure: SE**
Product of intensity of illumination (I_x) and storage time (s) when saturation of output voltage occurs.
3. **Photo response non-uniformity: PRNU**
The peak/bottom ratio to the average output voltage of all the valid bits calculated by the following formula.

$$PRNU (\%) = \left(\frac{V_{MAX. \text{ OR } V_{MIN.}} - 1}{\frac{1}{n} \sum_{j=1}^n V_j} \right) \times 100$$

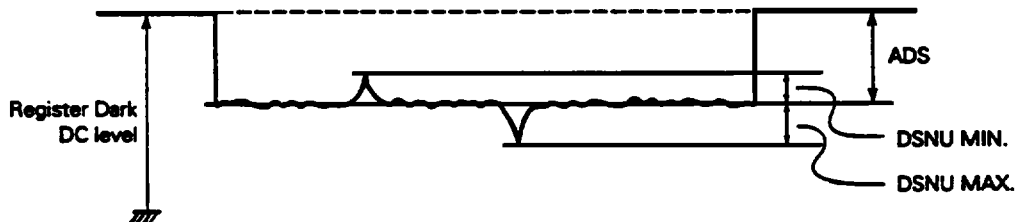
n : Number of valid bits
 V_j : Output voltage of each bit



4. **Average dark signal: ADS**
Output average voltage in light shielding

$$ADS(mV) = \frac{1}{n} \sum_{j=1}^n V_j$$

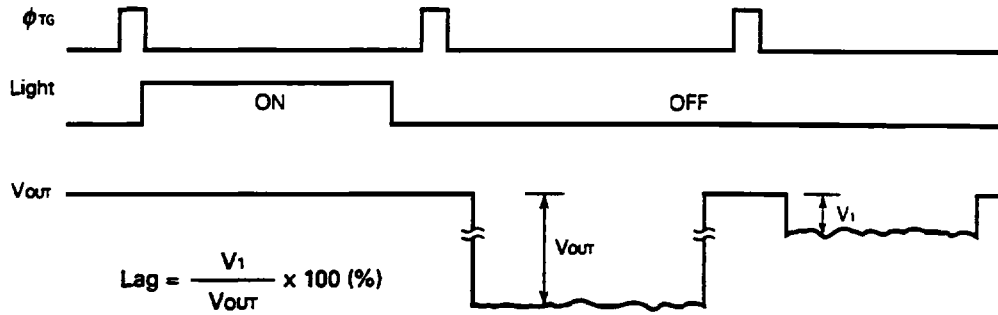
5. **Dark signal non-uniformity: DSNU**
The difference between peak or bottom output voltage in light shielding and ADS.



6. **Output impedance: Z_o**
Output pin impedance viewed from outside.
7. **Response: R**
Output voltage divided by exposure ($I_x \cdot s$).
Note that the response varies with the light source.

8. Image Lag: IL

The rate between the last output voltage and the next one after read out the data of a line.

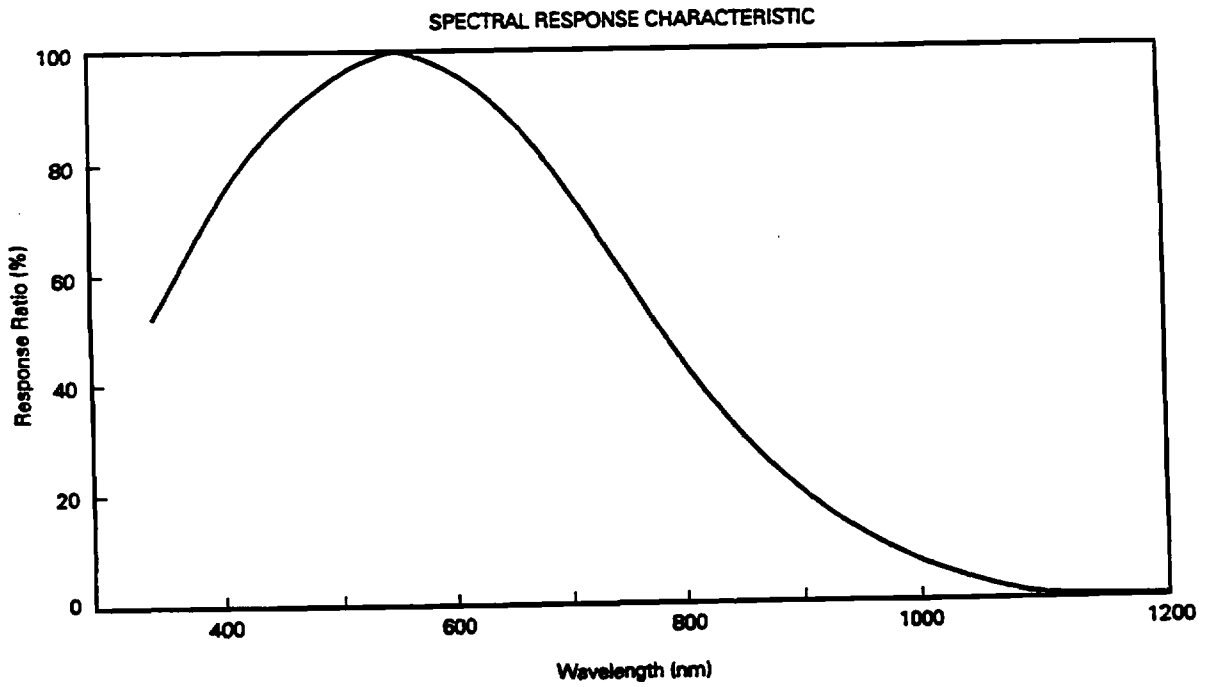
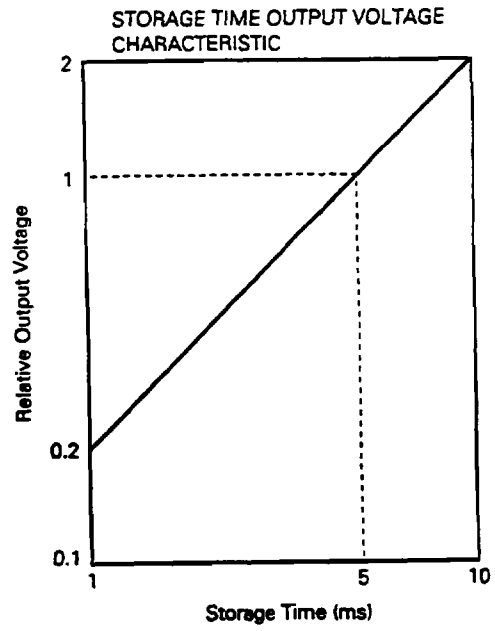
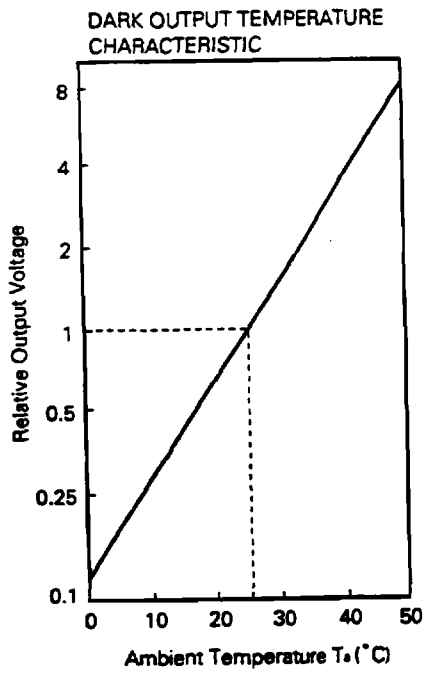


9. Resister Imbalance: RI

The rate of the average voltage which is the difference between the output voltage of Odd and Even bits, against the average output voltage of all the valid bits.

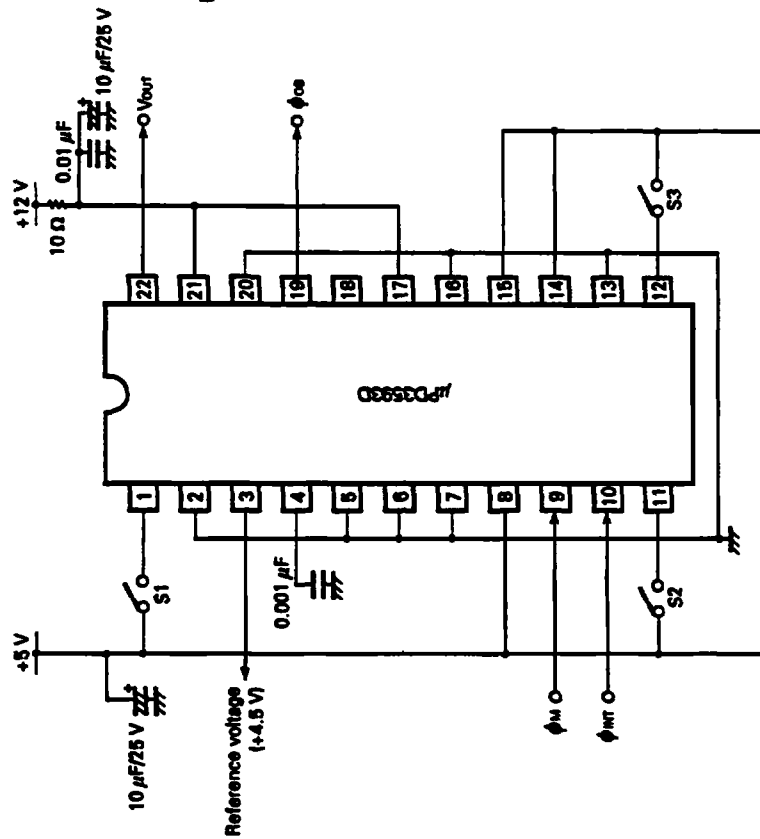
$$RI = \frac{\frac{1}{n} \sum_{j=1}^n |V_j - V_{j+1}|}{\frac{1}{n} \sum_{j=1}^n V_j} \times 100 (\%)$$

STANDARD CHARACTERISTIC CURVES ($T_a = 25^\circ\text{C}$)



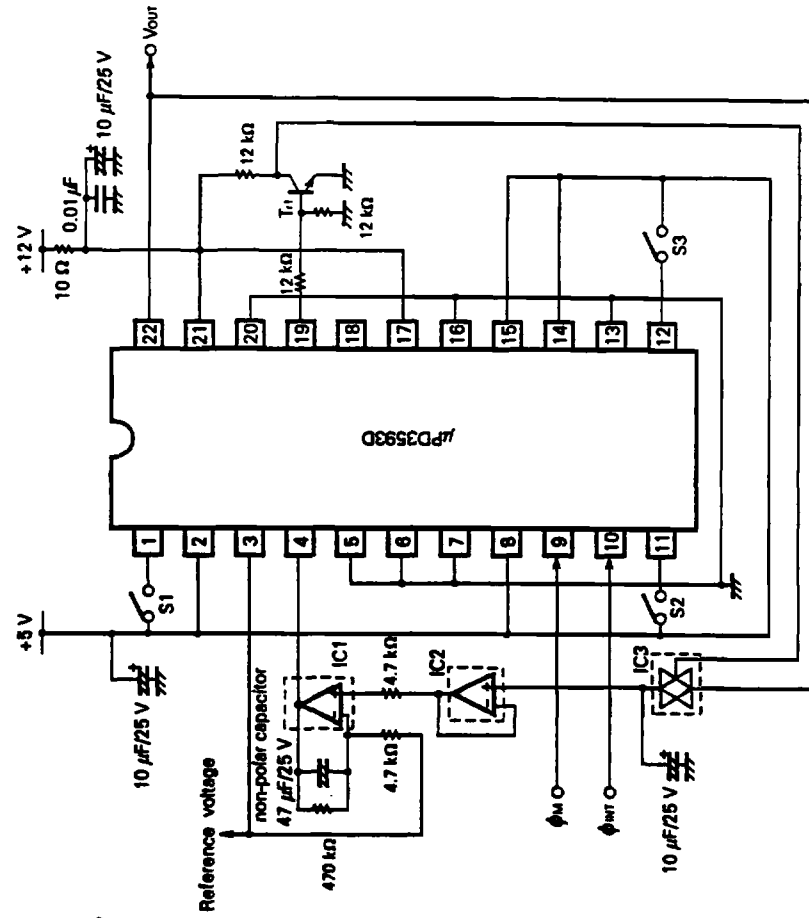
APPLICATION EXAMPLES

Example 1: With internal feedback clamp



- S1: Sample and hold use/unuse select switch
[OFF; Use ON; Unuse]
- S2, S3: Output amplifier gain select switch

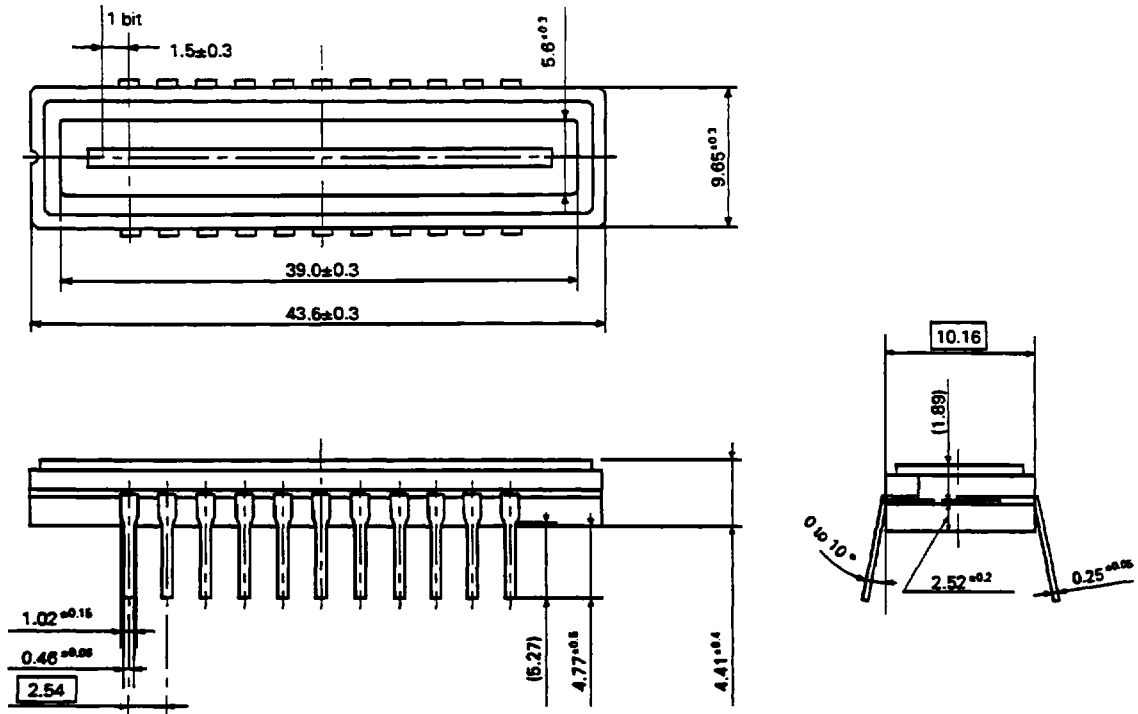
Example 2: Without internal feedback clamp



- IC1, IC2: Low offset, low input current
- IC3: μPD4066
- Tr1: 2SC945

The application circuits and their parameters are for references only and are not intended for use in actual design-in's.

PACKAGE DIMENSIONS (Unit: mm)



Name	Dimensions	Refractive index
Glass cap	42.2 x 9.0 x 0.5	1.5